


<b>Search Notes</b>  	<b>Application/Control No.</b>  10527376	<b>Applicant(s)/Patent Under Reexamination</b>  SHIMADA ET AL.
	<b>Examiner</b>  Erich A Leeser	<b>Art Unit</b>  1624

SEARCHED			
Class	Subclass	Date	Examiner
514	250, 257	10-27-08	EL
544	234, 250, 251, 344, 346	10-27-08	EL

SEARCH NOTES		
Search Notes	Date	Examiner
updated STN structure search, EAST class search, PALM inventor search	10-27-08	EL

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
514	250, 257	10-27-08	EL
544	234,250, 251, 344, 346	10-27-08	EL

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